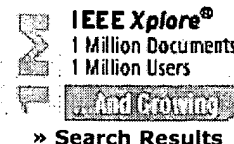




# IEEE Xplore®

RELEASE 1.8

Welcome  
United States Patent and Trademark Office



## Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

## Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

## Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

## Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

## IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet



Your search matched **14** of **1085387** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

### Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

leakage <and> current <and> x ray <and> ((electron <and>

☐ Check to search within this result set

*(and) beam (e-beam)*

### Results Key:

**JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard

#### 1 Low field leakage current and soft breakdown in ultra-thin gate oxides after heavy ions, electron or X-ray irradiation

Ceschia, M.; Paccagnella, A.; Sandrin, S.; Ghidini, G.; Wyss, J.; Lavale, M.; Flament, O.;

Nuclear Science, IEEE Transactions on, Volume: 47, Issue: 3, June 2000  
Pages:566 - 573

[\[Abstract\]](#) [\[PDF Full-Text \(456 KB\)\]](#) **IEEE JNL**

#### 2 Low field leakage current and soft breakdown in ultra-thin gate oxides after heavy ions, electrons or X-ray irradiation

Ceschia, M.; Paccagnella, A.; Sandrin, S.; Ghidini, G.; Wyss, J.; Lavale, M.; Flament, O.;

Radiation and Its Effects on Components and Systems, 1999. RADECS 99. 1999 Fifth European Conference on, 13-17 Sept. 1999  
Pages:233 - 240

[\[Abstract\]](#) [\[PDF Full-Text \(668 KB\)\]](#) **IEEE CNF**

#### 3 Structural and electrical properties of Al/sub 2/O/sub 3/-ZrO/sub 2/ gate dielectrics on silicon-on-insulator

Zhu, M.; Chen, P.; Fu, R.K.Y.; Liu, W.L.; Lin, C.L.; Chu, P.K.;

Junction Technology, 2004. IWJT '04. The Fourth International Workshop on, 15-16 March 2004  
Pages:289 - 292

[\[Abstract\]](#) [\[PDF Full-Text \(393 KB\)\]](#) **IEEE CNF**

#### 4 Ultra-thin epitaxial zirconia oxide on silicon with crystalline interface

Wang, S.J.; Ong, C.K.; Xu, S.Y.; Chen, P.;

Optoelectronic and Microelectronic Materials and Devices, 2000. COMMAD 2000. Proceedings Conference on, 6-8 Dec. 2000  
Pages:543 - 546